



288/1#2
Atty. Dkt. No. 039153-0405 (F0945) Letter
to
Draftsmen

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Uzodinma Okoroanyanwu et al.

Title: IMPROVING SEM INSPECTION
AND ANALYSIS OF PATTERNED
PHOTORESIST FEATURES

Appl. No.: 09/820,143 ✓

Filing Date: 03/28/2001 ✓

Examiner: Unknown

Art Unit: 2878

<p>CERTIFICATE OF MAILING</p> <p>I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on the date below.</p> <p><u>Deborah A. Kocorowski</u> (Printed Name)</p> <p><u>Deborah A. Kocorowski</u> (Signature)</p> <p><u>June 11, 2001</u> (Date of Deposit)</p>

Russell
7/3/01

TRANSMITTAL OF FORMAL DRAWINGS

Commissioner for Patents
Washington, D.C. 20231

ATTENTION: DRAWING REVIEW BRANCH

Sir:

Transmitted herewith are the formal drawings (4 sheets, Figures 1-5) for the above-identified application. The Official Draftsperson is respectfully requested to approve these drawings for entry into the application.

Respectfully submitted,

Date 6/11/2001

By Katherine Lee

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JUN 25 2001
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